TestForum 2011

Tuusula, Finland
22- 23 November, 2011

NTF Chairman
Knut Båtstoløkken,
Kitron

Financial Chair
Birger Schneider,
NI Engineering

Secretary Chair
Bengt Magnhagen,
Swedish Electronics

Marketing Chair
Jürgen Sedlacek,
Alvetec KonTest

Executive Committee Members

Knut Båtstoløkken,
Kitron

Birger Schneider,
NI Engineering

Bjørn B Larsen,
NTNU (On sabatical)

Stig-Gunnar Jensen,
Eltek Valere

Bengt Magnhagen,
Swedish Electronics

Artur Jutman,
Tallinn University of Technology

Mick Austin,
JTAG Technologies Finland

Jürgen Sedlacek,
Alvetec KonTest

Matti Kemppainen
Nokia Siemens Networks Oy

Test Forum 2011 Local Organizer

Mick Austin
JTAG Technologies
Phone: +358 9 4730 2670
Fax: +358 9 4730 2998
E-mail: mick@jtag.com

Partners of Nordic Test Forum

>minST
EXPERTKOMPETENS
MIKRO/NANO SYSTEMTEKNIK

SE BRANSCHORGANISATIONEN SVENSK ELEKTRONIK

NTF NORDIC TEST FORUM

Call for Papers / Presentations

The 2-day TestForum 2011, the 11th event in the series, is a major event for Test professionals in the Nordic area and Baltic states. Every year the TestForum is attended by the industry's key persons as well as by international vendors of test and measurement equipment and solutions.

The event will take place in Tuusula, Finland. Nordic Test Forum hereby cordially invites you to participate and submit your contribution to TestForum 2011, which includes (but is not limited to) the following topics:

- *Embedded Test*
- *Functional test*
- *AOI / AXI*
- *Test economics*
- *ICT / Flying Probe*
- *Boundary-Scan test*
- *Preventive test / Prognostics*
- *Best practices in manufacturing test*
- *ASIC: BIST / Mixed-signal / IDDQ / IDDT*
- *Board test SW, BIST, diagnostics*
- *Testing Lead Free Electronics*
- *Design to Test transfer / Design for Testing*
- *Quality methods and tools*
- *ESD*
- *Test efficiency and optimization*
- *Future technology trends and test challenges*
- *Data acquisition / collection / analysis*

Submissions

NTF seeks for full papers and/or presentations in the area of test of electronics, including *R&D*, *Application Contributions, Best Practices*, *Emerging Ideas*, etc. You are free to submit contributions outside the above topics as long as they stay within the field of electronics test. Focus shall be on new and upcoming challenges, opportunities and techniques rather than on particular products.

Proceedings

At the event, Nordic Test Forum will deliver on electronic format the accepted contributions of authors that wish to provide the corresponding materials.

The Format of the Event

- The event duration will be a two-day workshop and a small exhibition attached to it.
- November 21st on the evening there is the AGM of the NTF.
- The mix of presentations will decide the number of sessions.
- The presentations will be 30 minutes each: 25 minutes of speech and 5 minutes for questions and comments.
- During the exhibition, attendees will have a chance to see the latest equipment and talk to exhibitors.

Key Dates

- Abstract submission: **Deadline extended to 19th September 2011!**
- Notification of acceptance: **September 30th, 2011**
- Presentation slides: **October 28th, 2011**

Further Information and Submissions

Suzanne Holte
Phone: +45 4557 0705
Email: suzanne@nordictestforum.org

Visit the NTF web pages at:
http://www.nordictestforum.org

Photos: Gustavelund : visithelsinki/Anne Relander Niklas Sjöblom Joni Rousku